Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/580,808	SEZAN ET AL.	
Examiner	Art Unit	
Annan Q. Shang	2617	

	SEARCHED				
Class	Subclass	Date	Examiner		
725	87-94,100- 1-3	10/27/2005	A.S		
			_		
	•				

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u></u>		

(INCLUDING SEARCH	TES I STRATEGY	')
	DATE	EXMR
•		
	_	
·		
•		
···		
•		
	·	
•		
	•	